

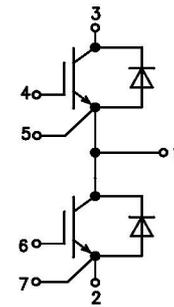
### 62 MM Trench-Field Stop IGBT Module

#### DESCRIPTION

HGF300MB75XXX designed for a 125°C junction Operation temperature, the module accommodates a Half bridge configuration of Planar Trench-FS IGBT and matching emitter controlled diodes.



V <sub>CES</sub>	V <sub>CEsat</sub>		I <sub>cn</sub> /I <sub>CRM</sub>
	T <sub>vj</sub> =25°C	1.5A	
750V	T <sub>vj</sub> = 125°C	1.7A	300A/600A



#### FEATURES

- Low switching losses
- V<sub>CEsat</sub> positive temperature coefficient
- High robustness
- 750V Trench-FS technology
- Isolated Base Plate
- Copper Base Plate
- Standard Housing

#### APPLICATIONS

- UPS
- Inductive heating
- High frequency switching

#### MAXIMUM RATED VALUES(IGBT)

Parameter	Symbol	Conditions	Values	Units
Collector-emitter voltage	V <sub>CES</sub>	T <sub>vj</sub> =25°C, V <sub>GE</sub> =0V	750	V
Continuous collector current	I <sub>cn</sub>	T <sub>c</sub> = 100°C, T <sub>vjmax</sub> = 150°C	300	A
Repetitive peak collector current	I <sub>CRM</sub>	t <sub>p</sub> = 1ms, T <sub>vj</sub> =25°C	600	A
Gate-emitter peak voltage	V <sub>GES</sub>	T <sub>vj</sub> =25°C	±20	V
SC data	I <sub>sc</sub>	V <sub>GE</sub> ≤15V, V <sub>CC</sub> =800V V <sub>CEmax</sub> =V <sub>CES</sub> -L <sub>s</sub> CE*di/dt, t <sub>p</sub> ≤10μs, T <sub>vj</sub> = 125°C	1200	A
Total power dissipation	P <sub>tot</sub>	T <sub>c</sub> =25°C, T <sub>vj max</sub> = 150°C	1250	W

1) Verified by characterization / design not by test.

**CHARACTERISTICS VALUES(IGBT)**

Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Collector-emitter saturation voltage	V <sub>CE sat</sub>	IC= 300A, V <sub>GE</sub> = 15V, T <sub>vj</sub> =25°C		1.5	2.0	V
		IC= 300A, V <sub>GE</sub> = 15V, T <sub>vj</sub> = 125°C		1.7		V
		IC= 300A, V <sub>GE</sub> = 15V, T <sub>vj</sub> = 150°C		1.75		V
Gate-emitter threshold voltage	V <sub>GETh</sub>	IC=4mA, V <sub>CE</sub> =V <sub>GE</sub> , T <sub>vj</sub> =25°C	5	6	7	V
Gate charge	QG	V <sub>GE</sub> =-8V...+15V		470		nC
Integrated gate resistor	RG	T <sub>vj</sub> =25°C		2.5		Ω
Input capacitance	C <sub>ies</sub>	T <sub>vj</sub> =25°C, f= 1MHz, V <sub>GE</sub> =0V, V <sub>CE</sub> =25V		28.5		nF
Output capacitance	C <sub>oes</sub>	T <sub>vj</sub> =25°C, f= 1MHz, V <sub>GE</sub> =0V, V <sub>CE</sub> =25V		1.9		nF
Reverse transfer capacitance	C <sub>res</sub>	T <sub>vj</sub> =25°C, f= 1MHz, V <sub>GE</sub> =0V, V <sub>CE</sub> =25V		0.85		nF
Collector-emitter cut-off current	IC <sub>ES</sub>	V <sub>CE</sub> = 750V, V <sub>GE</sub> =0V, T <sub>vj</sub> =25°C			100	μA
Gate-emitter leakage current	IG <sub>ES</sub>	V <sub>CE</sub> =0V, V <sub>GE</sub> =20V, T <sub>vj</sub> =25°C			200	nA
	IG <sub>ES</sub>	V <sub>CE</sub> =0V, V <sub>GE</sub> =30V, T <sub>vj</sub> =25°C			500	nA
Turn-on delay time, inductive load	t <sub>d on</sub>	IC= 300A, V <sub>CE</sub> =400V, V <sub>GE</sub> =-8V/+15V R <sub>Gon</sub> =5.1Ω, R <sub>Goff</sub> =5Ω	T <sub>vj</sub> =25°C	0.23		μs
			T <sub>vj</sub> = 125°C	0.26		μs
			T <sub>vj</sub> = 150°C	0.26		μs
Rise time, inductive load	t <sub>r</sub>		T <sub>vj</sub> =25°C	0.08		μs
			T <sub>vj</sub> = 125°C	0.1		μs
			T <sub>vj</sub> = 150°C	0.11		μs
Turn-off delay time, inductive load	t <sub>d off</sub>		T <sub>vj</sub> =25°C	0.53		μs
			T <sub>vj</sub> = 125°C	0.65		μs
			T <sub>vj</sub> = 150°C	0.68		μs
Fall time, inductive load	t <sub>f</sub>	T <sub>vj</sub> =25°C	0.11		μs	
		T <sub>vj</sub> = 125°C	0.13		μs	
		T <sub>vj</sub> = 150°C	0.14		μs	
Turn-on energy loss per pulse	E <sub>on</sub>	T <sub>vj</sub> =25°C	40.5		mJ	
		T <sub>vj</sub> = 125°C	52		mJ	
		T <sub>vj</sub> = 150°C	56		mJ	
Turn-off energy loss per pulse	E <sub>off</sub>	T <sub>vj</sub> =25°C	21.1		mJ	
		T <sub>vj</sub> =125°C	32.4		mJ	
		T <sub>vj</sub> = 150°C	38.2		mJ	
Thermal resistance, junction to heatsink	R <sub>thJc</sub>	per IGBT			0.12	K/W

**MAXIMUM RATED VALUES(FRD)**

Parameter	Symbol	Conditions	Values	Units
Repetitive peak reverse voltage	V <sub>RRM</sub>	T <sub>vj</sub> =25°C	750	V
Continuous forward current	I <sub>F</sub>	T <sub>C</sub> =100°C,T <sub>vjmax</sub> =150°C	300	A
Maximum repetitive forward current	I <sub>FRM</sub>	Pulse, t <sub>p</sub> = 1ms	600	A
I <sup>2</sup> t-value	I <sup>2</sup> t	V <sub>R</sub> =0V, t <sub>p</sub> = 10ms, T <sub>vj</sub> = 125°C	14000	A <sup>2</sup> s

**CHARACTERISTICS VALUES(FRD)**

Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Forward voltage	V <sub>F</sub>	I <sub>F</sub> =300A, V <sub>GE</sub> =0V,	T <sub>vj</sub> =25°C	1.33	1.8	V
			T <sub>vj</sub> = 125°C	1.38		V
			T <sub>vj</sub> = 150°C	1.43		V
Peak reverse recovery current	I <sub>RM</sub>		T <sub>vj</sub> =25°C	120		A
			T <sub>vj</sub> = 125°C	185		A
			T <sub>vj</sub> = 150°C	195		A
Recovered charge	Q <sub>r</sub>	I <sub>F</sub> =300A, V <sub>R</sub> =400V, V <sub>GE</sub> =-8V, di <sub>F</sub> /dt=500A/μs (T <sub>vj</sub> =150°C)	T <sub>vj</sub> =25°C	15.2		μC
			T <sub>vj</sub> = 125°C	22.5		μC
			T <sub>vj</sub> = 150°C	30.3		μC
Reverse recovery energy	E <sub>rec</sub>		T <sub>vj</sub> =25°C	4.4		mJ
			T <sub>vj</sub> = 125°C	7.2		mJ
			T <sub>vj</sub> = 150°C	8.9		mJ
Thermal resistance, junction to case	R <sub>thJC</sub>	per FRD			0.15	K/W

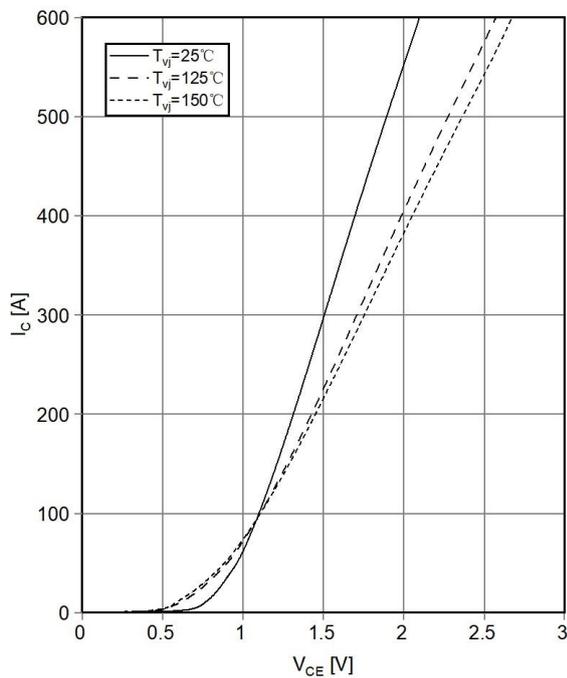
**CHARACTERISTICS VALUES(MODULE)**

Parameter	Symbol	Conditions	Values			Units
			Min.	Typ.	Max.	
Maximum junction temperature	T <sub>vj max</sub>				150	°C
Temperature under switching conditions	T <sub>vj op</sub>		-40		150	°C
Storage temperature	T <sub>stg</sub>		-40		125	°C
Stray inductance module	L <sub>sCE</sub>			20		nH
Module lead resistance, terminals-chip	R <sub>CC+EE</sub>	T <sub>vj</sub> =25°C, per switch		0.7		mΩ
Isolation test voltage	V <sub>isol</sub>	AC, RMS, f=50Hz, t= 1min		2.5		kV

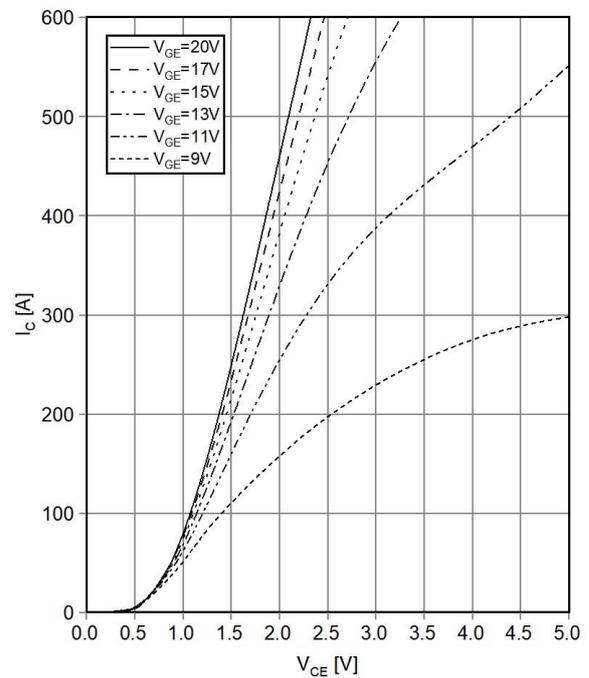
Creepage distance	ds	Terminal to terminal		29		mm
		Terminal to base		24		mm
Clearance distance in air	da	Terminal to terminal		24		mm
		Terminal to base		11		mm
Comperative tracking index	CTI			>400		
Mounting torque for module mounting	M1	Screw M5	3	-	6	N·m
Terminal connection torque	M2	Screw M6	2.5	-	5	N·m
Internal isolation	-	Basic insulation (class1, IEC 61140)	Al <sub>2</sub> O <sub>3</sub>			-
Material of module baseplate	-	-	Cu+Ni			-
Dimensions	LxWxH	-	106.4x61.4x30.9			mm
Weight	G	-	339			g

### CHARACTERISTICS DIAGRAMS

Output characteristic IGBT, Inverter(typical)  
I<sub>C</sub>=f(V<sub>CE</sub>), V<sub>GE</sub>=15V

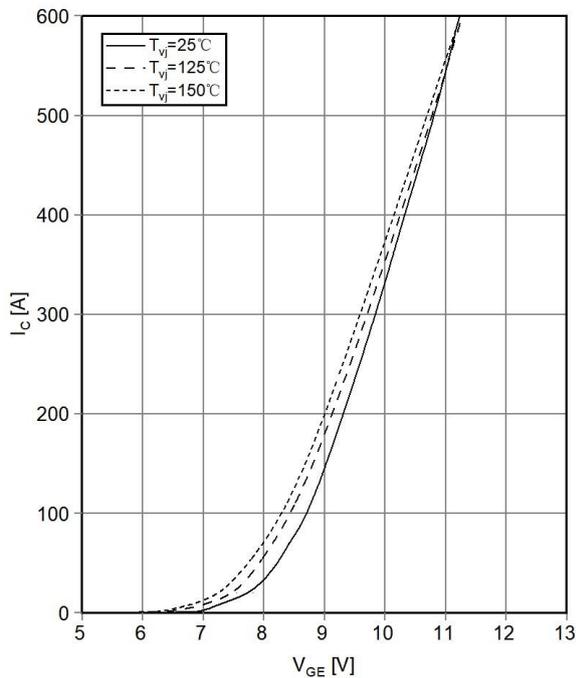


Output characteristic IGBT, Inverter(typical)  
I<sub>C</sub>=f(V<sub>CE</sub>), T<sub>vj</sub>=150°C



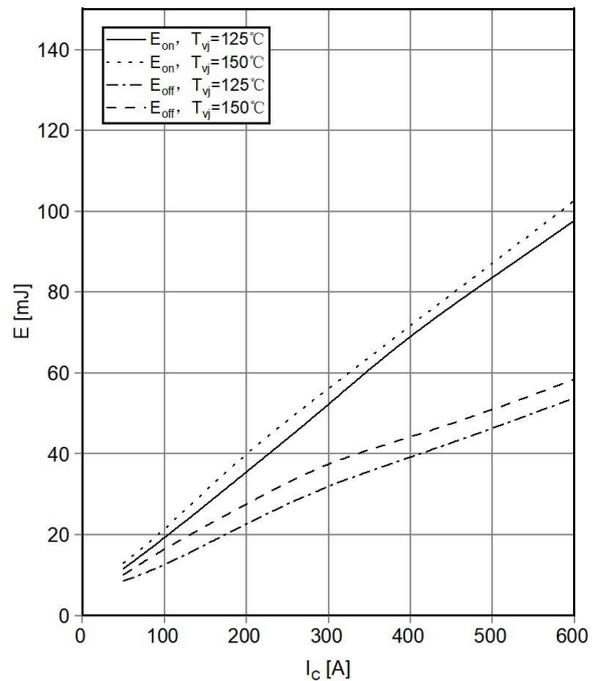
### Transfer characteristic IGBT, Inverter(typical)

$$I_c = f(V_{GE}), V_{CE} = 20V$$



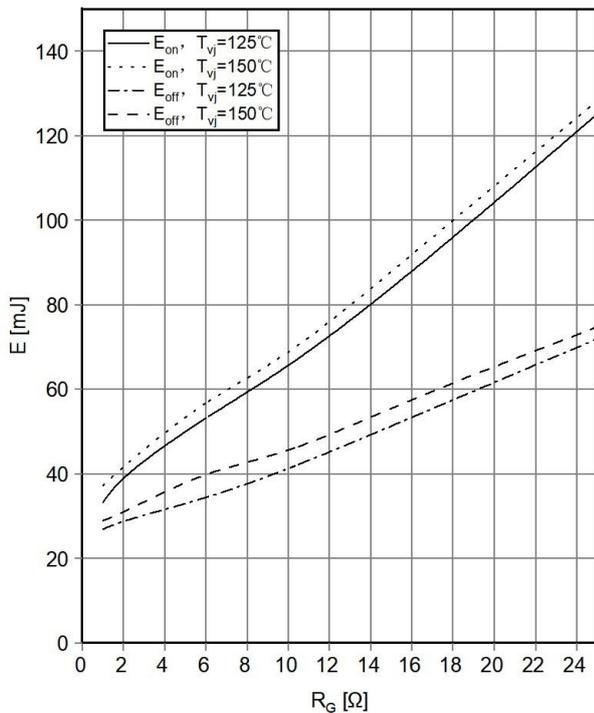
### Switching losses IGBT, Inverter(typical)

$$E_{on} = f(I_c), E_{off} = f(I_c), V_{GE} = -8V/+15V, R_{Gon} = 5.1\Omega, R_{Goff} = 5\Omega, V_{CE} = 400V$$



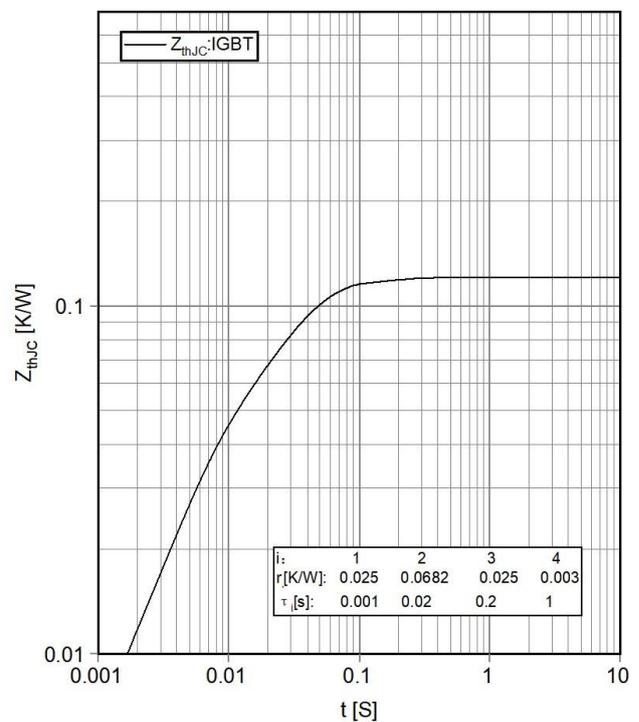
### Switching losses IGBT, Inverter(typical)

$$E_{on} = f(R_G), E_{off} = f(R_G), V_{GE} = -8/+15V, I_c = 300A, V_{CE} = 400V$$



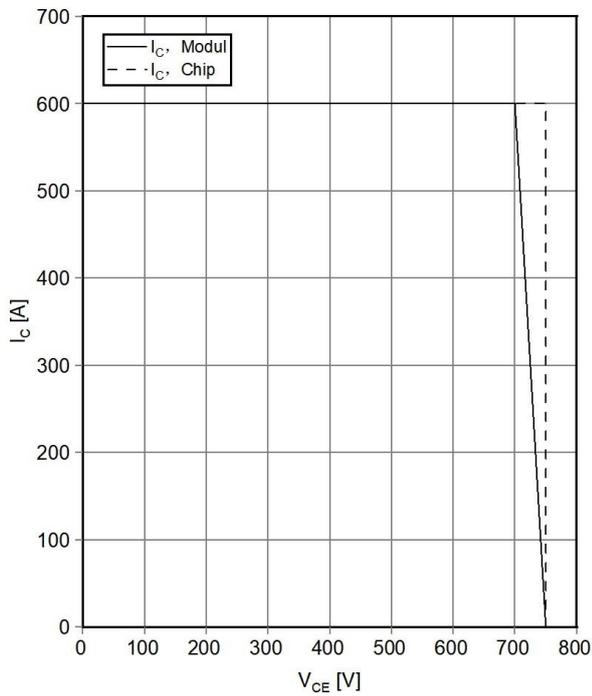
### Transient thermal impedance IGBT, Inverter

$$Z_{thJC} = f(t)$$



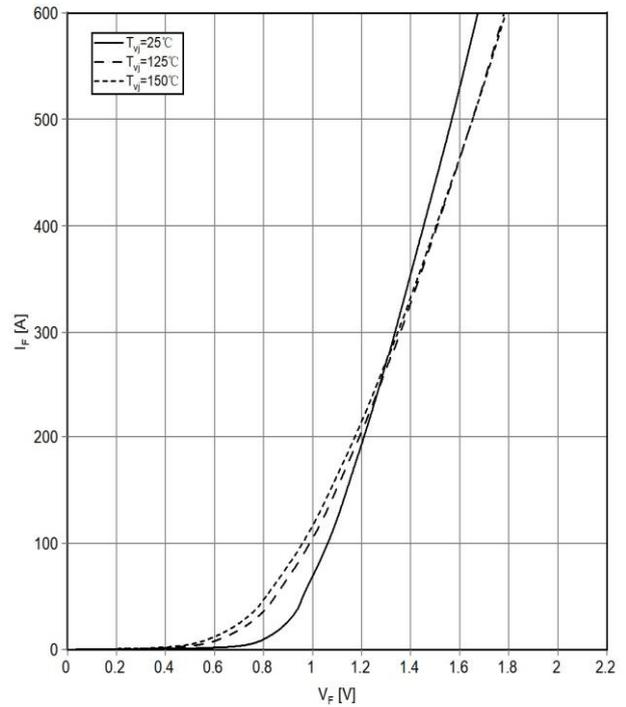
### Everse bias safe operating area IGBT, Inverter(RBSOA)

$I_C=f(V_{CE}), V_{GE}=15V, R_{Goff}=5\Omega, T_{vj}=150^\circ C$



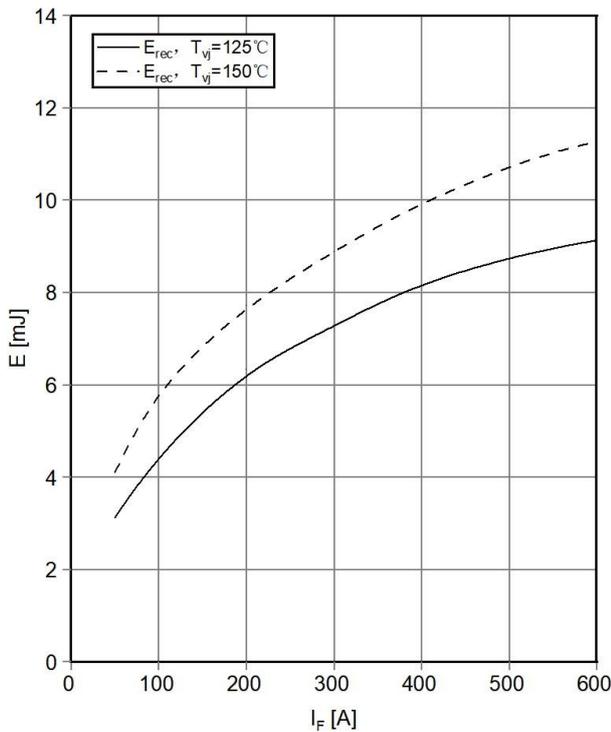
### Forward characteristic of FRD, Inverter(typical)

$I_F=f(V_F)$



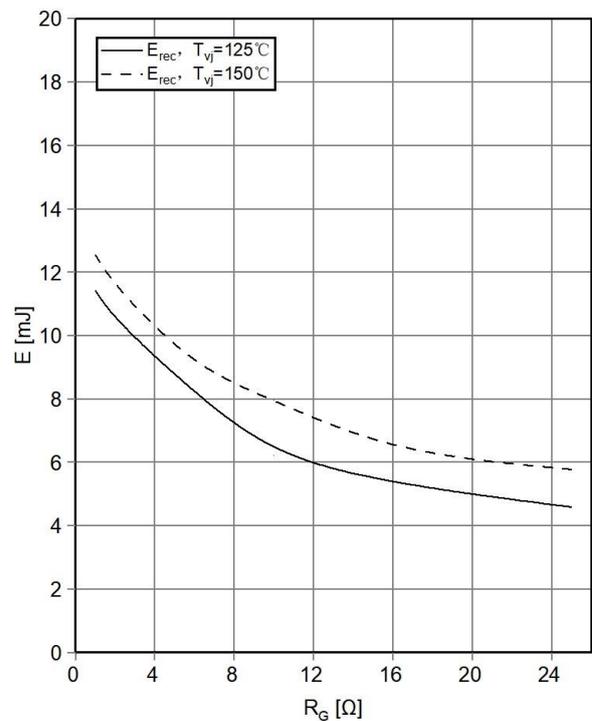
### Switching losses FRD, Inverter(typical)

$E_{rec}=f(I_F), R_{Gon}=5\Omega, V_{CE}=400V$



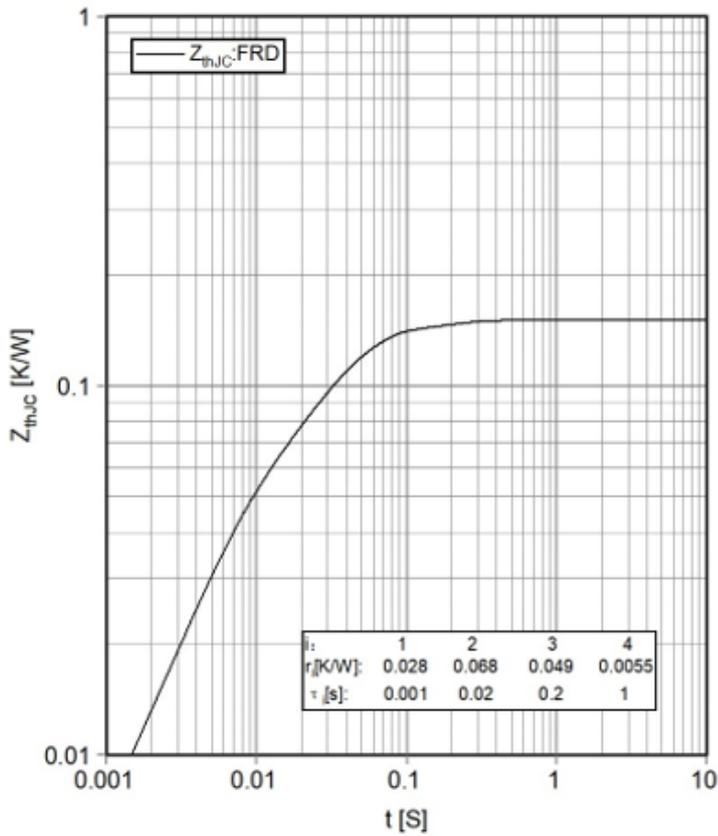
### Switching losses FRD, Inverter(typical)

$E_{rec}=f(R_G), I_F=300A, V_{CE}=400V$

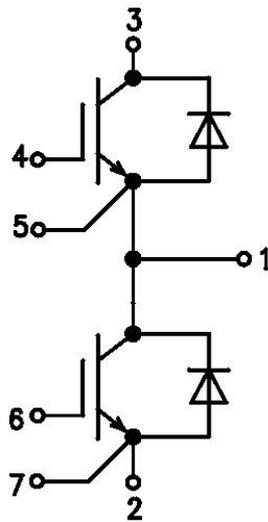


Transient thermal impedance FRD, Inverter

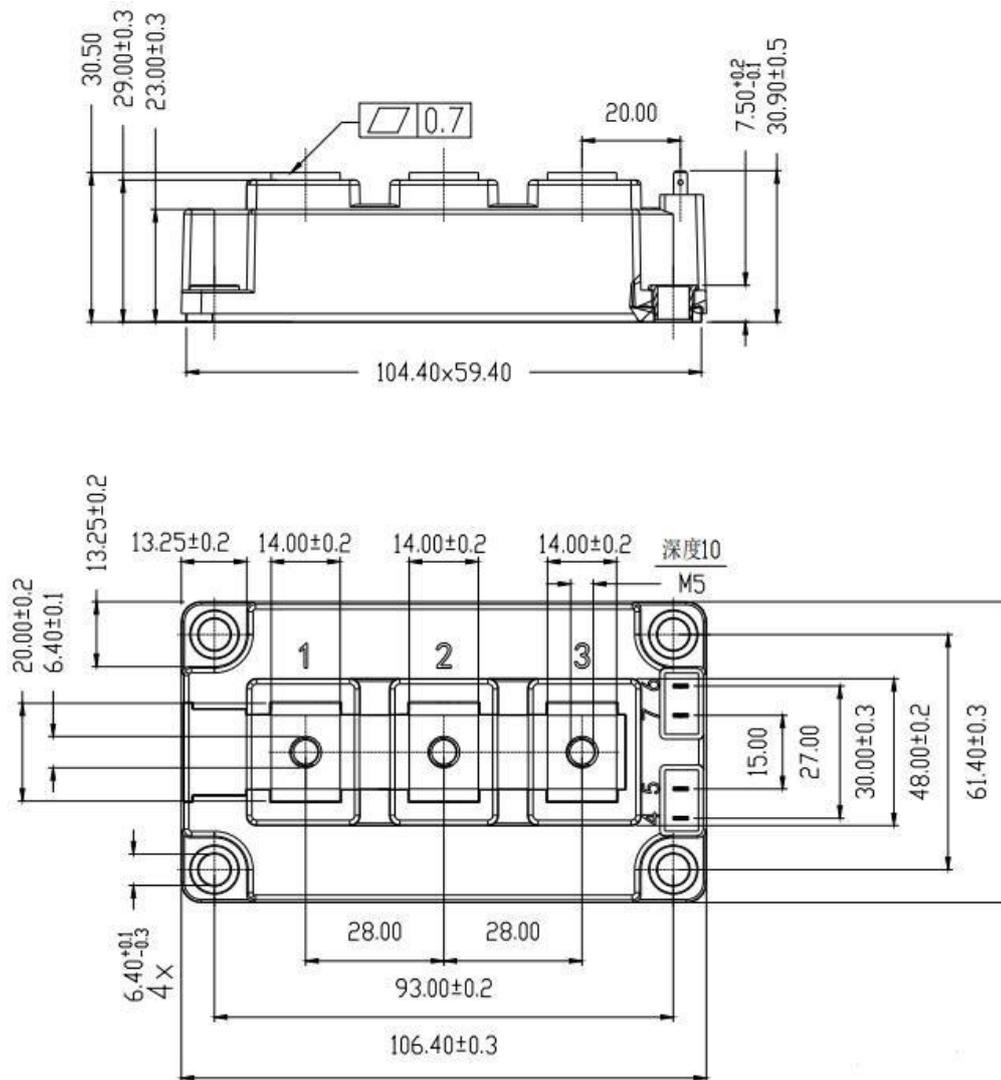
$Z_{thJC}=f(t)$



**CIRCUIT DIAGRAM**



PACKAGE OUTLINES



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Date of change	Rev #	revise content
2024/3/1	A/0	First version release